

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Atty. Docket

REINHOLD WIMBERGER-FRIEDL ET AL

NL 000774

Serial No.

Group Art Unit

Filed: CONCURRENTLY

Ex.

Title: A METHOD FOR INTRODUCING A GRID STRUCTURE

Commissioner for Patents
Washington, D.C. 20231

PRELIMINARY AMENDMENT

Sir:

Prior to calculation of the filing fee and examination, please amend the above-identified application as follows:

IN THE CLAIMS

Please amend the claims as follows:

3. A method as claimed in claim 1, where the grid structure is an X-ray scatter grid with successive regions having different X-ray absorption coefficients, characterized in that material strips exhibiting a different X-ray absorption behavior are used.

6. An examination apparatus (1) for irradiating an object (4) by means of X-rays (3), the examination apparatus (1) including an X-

ray source (2), an X-ray detector (8), a receiving space (5) for the object (4) to be irradiated, arranged between the X-ray source (2) and the X-ray detector (8) and an X-ray scatter grid (6) with successive regions of different X-ray absorptivity (3), said X-ray scatter grid to be arranged between the object (4) and the X-ray detector (8), characterized in that said X-ray scatter grid is manufactured according to claim 3.

REMARKS

The foregoing amendments to the claims were made solely to avoid filing the claims in the multiple dependent form so as to avoid the additional filing fee.

The claims were not amended in order to address issues of patentability and Applicants respectfully reserve all rights they may have under the Doctrine of Equivalents. Applicants furthermore reserve their right to reintroduce subject matter deleted herein at a later time during the prosecution of this application or continuing applications.

Respectfully submitted,

By 

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APPENDIX

3. A method as claimed in claim ~~1 or 2~~, where the grid structure is an X-ray scatter grid with successive regions having different X-ray absorption coefficients, characterized in that material strips exhibiting a different X-ray absorption behavior are used.

6. An examination apparatus (1) for irradiating an object (4) by means of X-rays (3), the examination apparatus (1) including an X-ray source (2), an X-ray detector (8), a receiving space (5) for the object (4) to be irradiated, arranged between the X-ray source (2) and the X-ray detector (8) and an X-ray scatter grid (6) with successive regions of different X-ray absorptivity (3), said X-ray scatter grid to be arranged between the object (4) and the X-ray detector (8), characterized in that said X-ray scatter grid is manufactured according to ~~one of the preceding claims 3 to 5~~claim 3.